

10/084338

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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10084338	FILING DATE 02/28/2002	CLASS 714	SUBCLASS 733	GAU 2133	EXAMINER J. KERNER
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**APPLICANTS: Matsuo Yukikazu; Nagura Yoshihiro;
RS

**CONTINUING DATA VERIFIED: NONE
JL 6/24/04

** FOREIGN APPLICATIONS VERIFIED: YES
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JAPAN 2001-224899 07/25/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO 50090-478
35 USC 119 conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	
Verified and Acknowledged Examiners's initials		

TITLE : Testing device of semiconductor integrated circuit and test method therefor

U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G.
Assistant Examiner			
ISSUE FEE		DRAWING	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.
		Print Fig.	
Primary Examiner		Application Examiner	
PREPARED FOR ISSUE			
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